

Heiko MÃ¼ller

List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/11169340/publications.pdf>

Version: 2024-02-01

13
papers

421
citations

1163117

8
h-index

1125743

13
g-index

14
all docs

14
docs citations

14
times ranked

565
citing authors

#	ARTICLE	IF	CITATIONS
1	Exploiting the full potential of the advanced two-hexapole corrector for STEM exemplified at 60kV. Ultramicroscopy, 2022, 233, 113440.	1.9	5
2	Advancing the Hexapole Cs-Corrector for the Transmission Electron Microscope. Microscopy and Microanalysis, 2020, 26, 2150-2151.	0.4	1
3	Test and characterization of a new post-column imaging energy filter. Advances in Imaging and Electron Physics, 2019, 212, 35-70.	0.2	14
4	The Dresden in-situ (S)TEM special with a continuous-flow liquid-helium cryostat. Ultramicroscopy, 2019, 203, 12-20.	1.9	1
5	Performance of the SALVE-microscope: Atomic-resolution TEM Imaging at 20 kV. Microscopy and Microanalysis, 2016, 22, 878-879.	0.4	6
6	Chromatic Aberration Correction for Atomic Resolution TEM Imaging from 20 to 80ÅkV. Physical Review Letters, 2016, 117, 076101.	7.8	99
7	A flexible multi-stimuli in situ (S)TEM: Concept, optical performance, and outlook. Ultramicroscopy, 2015, 151, 31-36.	1.9	9
8	On Proper Phase Contrast Imaging in Aberration Corrected TEM. Microscopy and Microanalysis, 2014, 20, 926-927.	0.4	2
9	Thermal Magnetic Field Noise Limits Resolution in Transmission Electron Microscopy. Physical Review Letters, 2013, 111, 046101.	7.8	97
10	Aplanatic imaging systems for the transmission electron microscope. Nuclear Instruments and Methods in Physics Research, Section A: Accelerators, Spectrometers, Detectors and Associated Equipment, 2011, 645, 20-27.	1.6	32
11	Aberration-corrected optics: from an idea to a device. Physics Procedia, 2008, 1, 167-178.	1.2	17
12	Chapter 2 Present and Future Hexapole Aberration Correctors for High-Resolution Electron Microscopy. Advances in Imaging and Electron Physics, 2008, , 43-119.	0.2	35
13	Advancing the Hexapole Cs-Corrector for the Scanning Transmission Electron Microscope. Microscopy and Microanalysis, 2006, 12, 442-455.	0.4	103